

RoHS COMPLIANT HALOGEN

FREE

## SW09R08V-VB Datasheet

## N-Channel 80 V (D-S) MOSFET

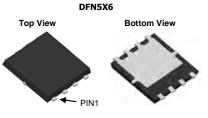
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)		
	0.0048 at $V_{GS}$ = 10 V	60			
80	0.0050 at V <sub>GS</sub> = 7.5 V	60	25 nC		
	0.0064 at V <sub>GS</sub> = 4.5 V	60			

#### **FEATURES**

- Trench power MOSFET
- 100 %  $R_q$  and UIS tested

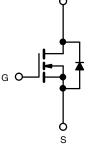
#### **APPLICATIONS**

- · Primary side switching
- Synchronous rectification
- DC/AC inverters



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Ton View



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N-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	80	v	
Gate-Source Voltage		V <sub>GS</sub>	± 20	v
	T <sub>C</sub> = 25 °C		60 <sup>a</sup>	
	T <sub>C</sub> = 70 °C		60 <sup>a</sup>	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	23.8 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		19 <sup>b, c</sup>	_
Pulsed Drain Current (t = 300 µs)	•	I <sub>DM</sub>	100	— A
Continuous Course Drain Diada Current	T <sub>C</sub> = 25 °C		60 <sup>a</sup>	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	5.6 <sup>b, c</sup>	
Single Pulse Avalanche Current		I <sub>AS</sub>	35	
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	61	mJ
	T <sub>C</sub> = 25 °C		104	
Mauianua Davian Diasination	T <sub>C</sub> = 70 °C		66.6	24
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	6.25 <sup>b, c</sup>	— W
	T <sub>A</sub> = 70 °C		4 b, c	
Operating Junction and Storage Temperature R	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C	
Soldering Recommendations (Peak Temperatur		260		

THERMAL RESISTANCE RATINGS								
Parameter		Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient b, f	t ≤ 10 s	R <sub>thJA</sub>	15	20	°C/W			
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	0.9	1.2	0/10			

Notes

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s. d. The DFN 5Xx6 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.

f. Maximum under steady state conditions is 54 °C/W.

SPECIFICATIONS (T <sub>J</sub> = 25 °C, unless otherwise noted)   Parameter Symbol Test Conditions Min. Typ. Max.							
Static	Symbol	Test conditions	IVIIII.	тур.	IVIAX.	Unit	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	80	-	_	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	VGS = 0 V, ID = 230 µA	-	47	-	v	
		I <sub>D</sub> = 250 μA		-5.7	-	mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		- 1.2	-5.7	-	V	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$		-	2.8	-	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			10	μA	
On State Duain Current 8		$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$		-	10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 V, V_{GS} = 10 V$	30	-	-	A	
			$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$ - 0.0048				
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 7.5 \text{ V}, I_D = 20 \text{ A}$	-	0.0050	-	Ω	
		$V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$	-	0.0064	-	<u> </u>	
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$	-	68	-	S	
Dynamic <sup>b</sup>	1		[	r		r	
Input Capacitance	C <sub>iss</sub>		-	2800	-	pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	1100	-		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	93	-		
	Qg	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$	-	57	86	1	
Total Gate Charge		$V_{DS}$ = 40 V, $V_{GS}$ = 7.5 V, $I_{D}$ = 20 A	-	42	63	nC	
			-	25	38		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$	-	8.5	-		
Gate-Drain Charge	Q <sub>gd</sub>		-	10	-		
Output Charge	Q <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$	-	70	105		
Gate Resistance	Rg	f = 1 MHz	0.3	0.95	1.9	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>		I	9	18	- ns	
Rise Time	tr	$V_{DD}$ = 40 V, $R_L$ = 2 $\Omega$	I	12	24		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ 20 A, $V_{GEN}$ = 10 V, $R_g$ = 1 $\Omega$	-	34	68		
Fall Time	t <sub>f</sub>		-	7	14		
Turn-On Delay Time	t <sub>d(on)</sub>		-	16	32		
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, \text{ R}_{L} = 2 \Omega$	-	15	30		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ 20 A, $V_{GEN}$ = 7.5 V, $R_g$ = 1 $\Omega$	-	32	64		
Fall Time	t <sub>f</sub>		-	8	16		
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C	-	-	60		
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	-	-	-	100	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 5 A	-	0.73	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	÷	-	53	105	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		-	65	130	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 20 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$	-	25	-		
Reverse Recovery Rise Time	t <sub>b</sub>		-	28		ns	

#### Notes

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

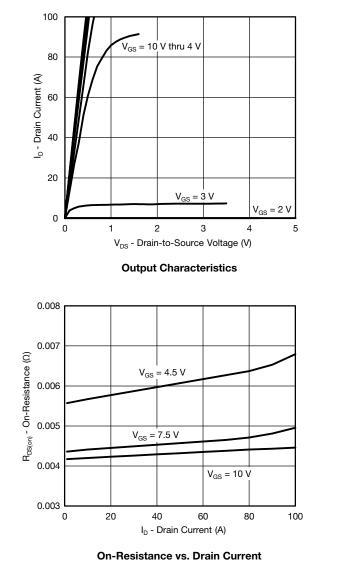
b. Guaranteed by design, not subject to production testing.

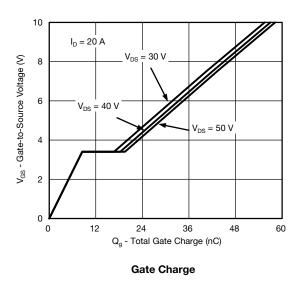
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

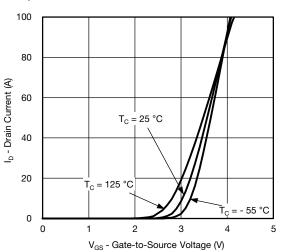
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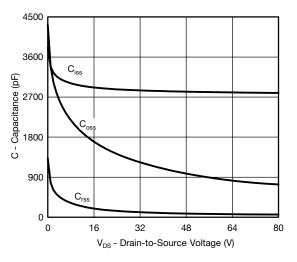




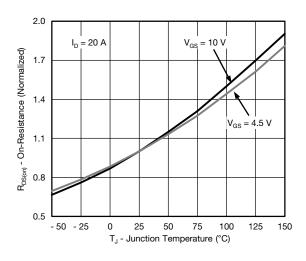




**Transfer Characteristics** 

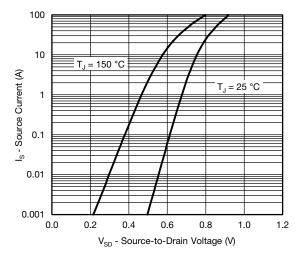




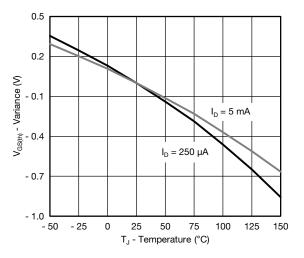


**On-Resistance vs. Junction Temperature** 

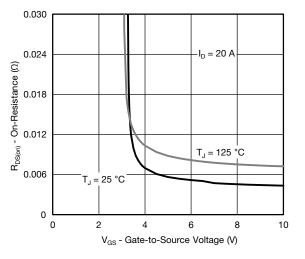




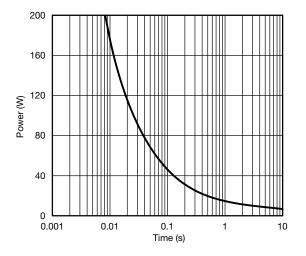
Source-Drain Diode Forward Voltage



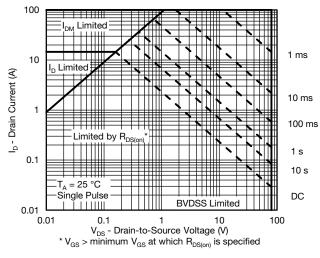




**On-Resistance vs. Gate-to-Source Voltage** 

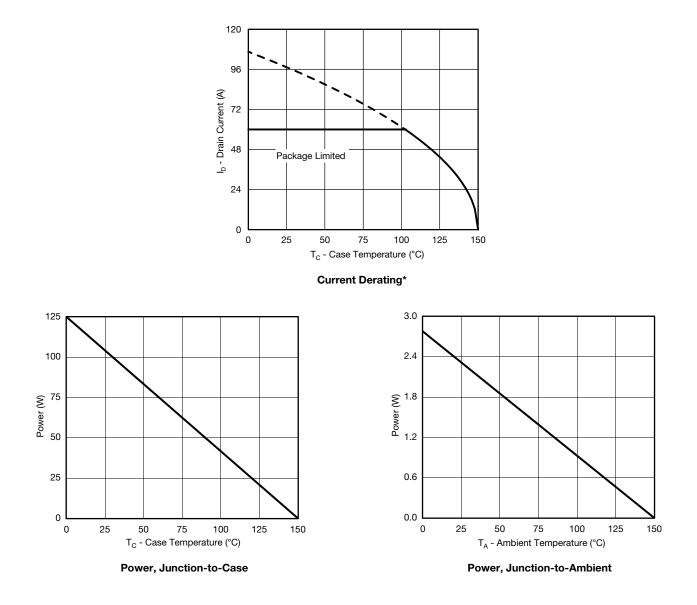


Single Pulse Power, Junction-to-Ambient



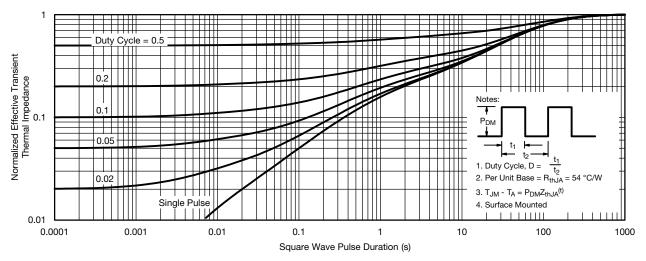
Safe Operating Area, Junction-to-Ambient

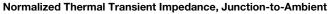


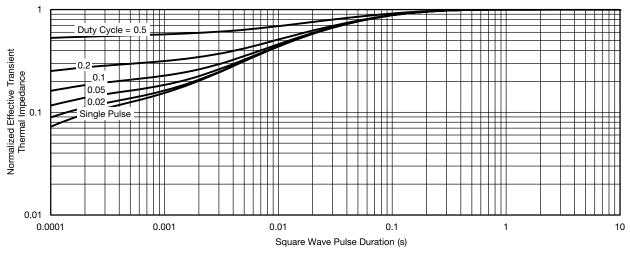


\* The power dissipation  $P_D$  is based on  $T_{J \text{ (max.)}} = 150 \text{ °C}$ , using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





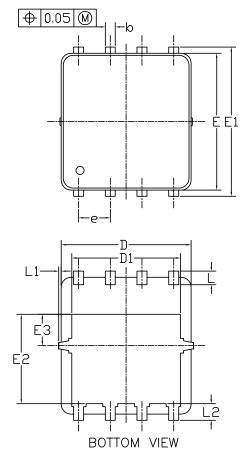


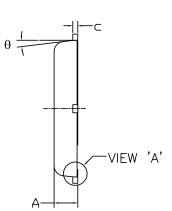


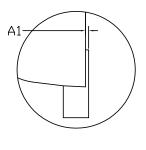
Normalized Thermal Transient Impedance, Junction-to-Case





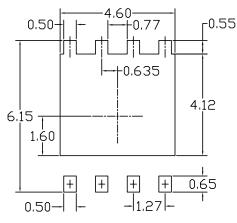






<u>VIEW 'A'</u> (SCALE 5:1)

RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS DIMENSIONS IN INC			CHES		
STMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
A	0.85	0.95	1.00	0.033	0.037	0.039
A1	0.00		0.05	0.000		0.002
b	0.30	0.40	0.50	0.012	0.016	0.020
с	0.15	0.20	0.25	0.006	0.008	0.010
D	5.10	5.20	5.30	0.201	0.205	0.209
D1	4.25	4.35	4.45	0.167	0.171	0.175
E	5.45	5.55	5.65	0.215	0.219	0.222
E1	5.95	6.05	6.15	0.234	0.238	0.242
E2	3.525	3.625	3.725	0.139	0.143	0.147
E3	1.175	1.275	1.375	0.046	0.050	0.054
e	1.27 BSC			0.050 BSC		
L	0.45	0.55	0.65	0.018	0.022	0.026
L1	0		0.15	0		0.006
L2	0.68 REF			0.027 REF		
θ	0°		10°	0°		10°

NOTE

UNIT: mm

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.

MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH. 2. CONTROLLING DIMENSION IS MILLIMETER.

CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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